## **EAST Search History**

| Ref<br># | Hits | Search Query  | DBs                                    | Default<br>Operator | Plurals<br>· | Time Stamp       |
|----------|------|---|--|---------------------|--------------|------------------|
| L1       | 359  | 702/167   | US-PGPUB;<br>USPAT;<br>EPO;<br>DERWENT | OR                  | ON           | 2007/09/20 07:25 |
| L2       | 220  | 702/168   | US-PGPUB;<br>USPAT;<br>EPO;<br>DERWENT | OR                  | ON           | 2007/09/20 07:25 |
| L3       | 1777 | 702/150   | US-PGPUB;<br>USPAT;<br>EPO;<br>DERWENT | OR                  | ON           | 2007/09/20 07:25 |
| L4       | 713  | 702/155   | US-PGPUB;<br>USPAT;<br>EPO;<br>DERWENT | OR                  | ON           | 2007/09/20 07:26 |
| L5       | 5    | measuring with ((three adj<br>dimensional) or (3D)) with (surface<br>with shape) and ((workpiece) or<br>(semiconductor with wafer)) and<br>((record) or (recording) or (recorder)<br>or (recorded))and ((trace) or<br>(tracing))      | US-PGPUB;<br>USPAT;<br>EPO;<br>DERWENT | OR                  | ON           | 2007/09/20 07:28 |
| L6       | 1    | measuring with ((three adj<br>dimensional) or (3D)) with (surface<br>with shape) and ((workpiece) or<br>(semiconductor with wafer)) and<br>((record) or (recording) or (recorder)<br>or (recorded))and ((trace) or<br>(tracing)).CLM. | US-PGPUB;<br>USPAT;<br>EPO;<br>DERWENT | OR                  | ON           | 2007/09/20 07:29 |
| L7       | 4    | measuring with ((three adj<br>dimensional) or (3D)) same (surface<br>with shape) and ((workpiece) or<br>(semiconductor with wafer)) and<br>((record) or (recording) or (recorder)<br>or (recorded))and ((trace) or                    | US-PGPUB;<br>USPAT;<br>EPO;<br>DERWENT | OR                  | ON           | 2007/09/20 07:36 |
|          |      | (tracing)) and predetermined  |  |                     |              |                  |
| L8       | 24   | measuring with ((three adj<br>dimensional) or (3D)) same (surface<br>with shape) and ((workpiece) or<br>(semiconductor with wafer)) and<br>((record) or (recording) or (recorder)<br>or (recorded))and ((block) or<br>(portion))      | US-PGPUB;<br>USPAT;<br>EPO;<br>DERWENT | OR .                | ON           | 2007/09/20 07:37 |

Page 1 9/20/07 7:48:58 AM
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## **EAST Search History**

| L9 | 1 | measuring with ((three adj<br>dimensional) or (3D)) same (surface<br>with shape) and ((workpiece) or<br>(semiconductor with wafer)) and<br>((record) or (recording) or (recorder)<br>or (recorded))and ((block) or<br>(portion)) and ((duplicate) or<br>(duplicating) or (duplicated)) | US-PGPUB;<br>USPAT;<br>EPO;<br>DERWENT | OR | ON | 2007/09/20 07:48 |
|----|---|--|--|----|----|------------------|
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9/20/07 7:48:58 AM C:\Documents and Settings\bbui\My Documents\EAST\Workspaces\10562969.wsp Page 2